August 2014



FQA38N30 N-Channel QFET[®] MOSFET 300 V, 38.4 A, 85 mΩ

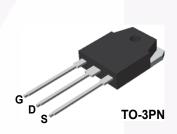
Features

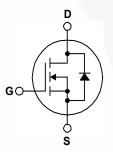
- 38.4 A, 300 V, $\mathsf{R}_{\mathsf{DS}(\mathsf{on})}$ = 85 m Ω (Max.) @ V_GS = 10 V, I_D = 19.2 A
- Low Gate Charge (Typ. 90 nC)
- Low Crss (Typ. 70 pF)
- 100% Avalanche Tested
- RoHS compliant

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supply, power factor correction, electronic lamp ballast based on half bridge.





Absolute Maximum Ratings T_c = 25°C unless otherwise noted.

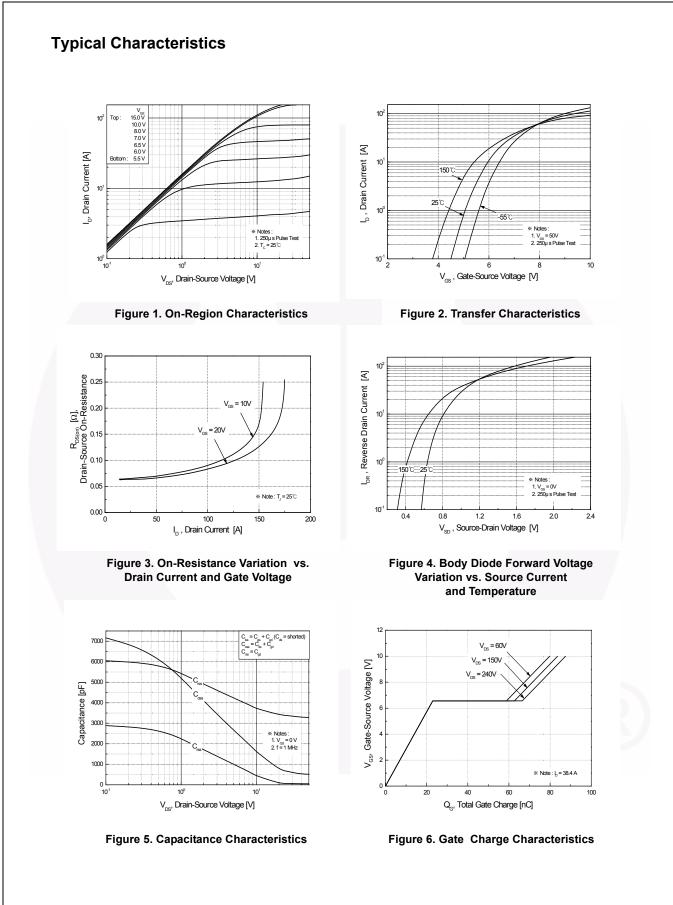
Symbol	Parameter	FQA38N30	Unit	
V _{DSS}	Drain-Source Voltage	300	V	
D	Drain Current - Continuous ($T_C = 25^{\circ}C$)		38.4	A
	- Continuous (T _C = 100°C)		24.3	A
DM	Drain Current - Pulsed	(Note 1)	153.6	A
/ _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	1500	mJ
AR	Avalanche Current	(Note 1)	38.4	A
- AR	Repetitive Avalanche Energy	(Note 1)	29	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
D	Power Dissipation ($T_C = 25^{\circ}C$)		290	W
	- Derate above 25°C		2.33	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
Γ _L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C

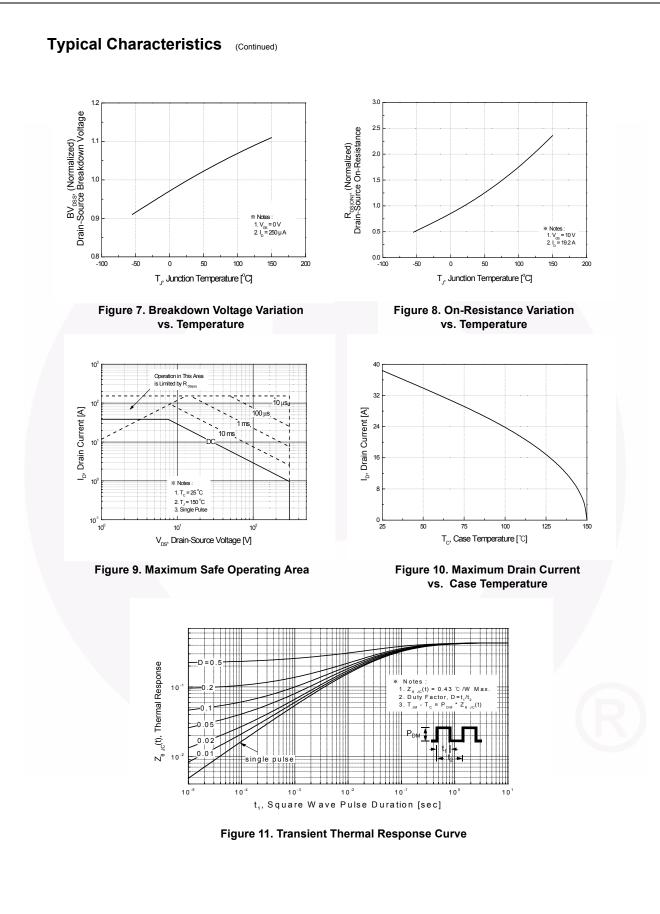
Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit	
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case		0.43	°C/W	
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W	
R _{0JA} Thermal Resistance, Junction-to-Ambient			40	°C/W	

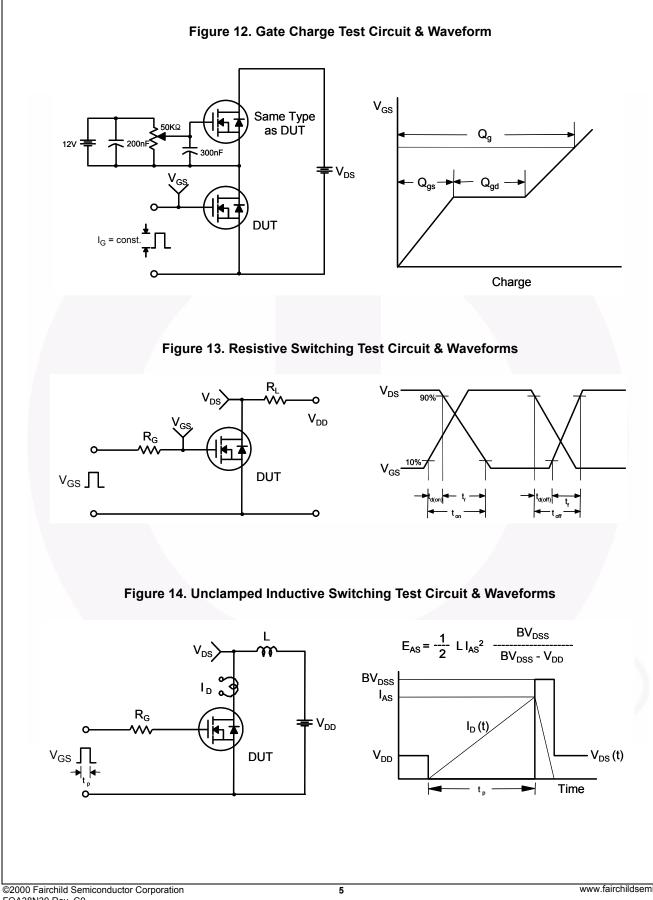
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		Packa	• •		e Tape Width		Qu	Quantity		
		TO-3P					30 units			
Electric	al Char	acteristics T _c = :	25°C unle	ss of	therwise noted.					
Symbol		Parameter			Test Conditions	5	Min.	Тур.	Max.	Uni
Off Cha	ractoristi	re la								
BV _{DSS}	aracteristics Drain-Source Breakdown Voltage			V _{GS} = 0 V, I _D = 250 μA			300			V
$\Delta BV_{DSS}/$				VGS - 0 V, ID - 200 µA			000			v
ΔT_{J}	cient	i voltage remperature c	Joeni-	I _D =	250 µA, Referenced t	o 25°C		0.35		V/°C
I _{DSS}				V _{DS} = 300 V, V _{GS} = 0 V				1	μA	
000	Zero Gate Voltage Drain Current			$V_{DS} = 240 \text{ V}, T_{C} = 125^{\circ}\text{C}$				10	μA	
I _{GSSF}	Gate-Body	Leakage Current, Forw		$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$					100	nA
I _{GSSR}	-	Leakage Current, Reve			= -30 V, V _{DS} = 0 V				-100	nA
0001				00						
On Cha	racteristic	cs								
V _{GS(th)}	Gate Threshold Voltage			V _{DS}	$= V_{GS}, I_D = 250 \ \mu A$		3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance			V _{GS} = 10 V, I _D = 19.2 A				0.065	0.085	Ω
9 _{FS}	Forward T	ransconductance		V _{DS}	= 50 V, I _D = 19.2 A			24		S
Dynami _{Ciss}	c Charact			.,	05.14.14		_	3380	4400	pF
C _{oss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance			V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz			670	870	pF	
C _{rss}							70	90	pF	
Orss	ILEVEISE I							70	30	р
Switchi	ng Charao	cteristics								
t _{d(on)}	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time			V_{DD} = 150 V, I _D = 38.4 A, R _G = 25 Ω			80	170	ns	
t _r							430	870	ns	
t _{d(off)}							170	350	ns	
t _f	Turn-Off Fa	all Time		(Note 4)		(Note 4)	-	190	390	ns
Qg	Total Gate	Charge		V_{DS} = 240 V, I _D = 38.4 A, V _{GS} = 10 V			90	120	nC	
Q _{gs}	Gate-Sour	ce Charge	[-		23		nC
Q _{gd}	Gate-Drain Charge			(Note 4)			44		nC	
Drain-S	ource Dio	de Characteristics	s and M	axi	mum Ratings					
I _S	Maximum Continuous Drain-Source Diode				•				38.4	А
I _{SM}	Maximum Pulsed Drain-Source Diode Fo							153.6	A	
V _{SD}	Drain-Source Diode Forward Voltage			V _{GS} = 0 V, I _S = 38.4 A				1.5	V	
t _{rr}	Reverse Recovery Time		-	$V_{GS} = 0 V, I_S = 38.4 A,$ $dI_F / dt = 100 A/\mu s$			300		ns	
Q _{rr}		Recovery Charge					2.85		μC	
otes :		,								
	ina : nulse width	limited by maximum junction ter	moerature							





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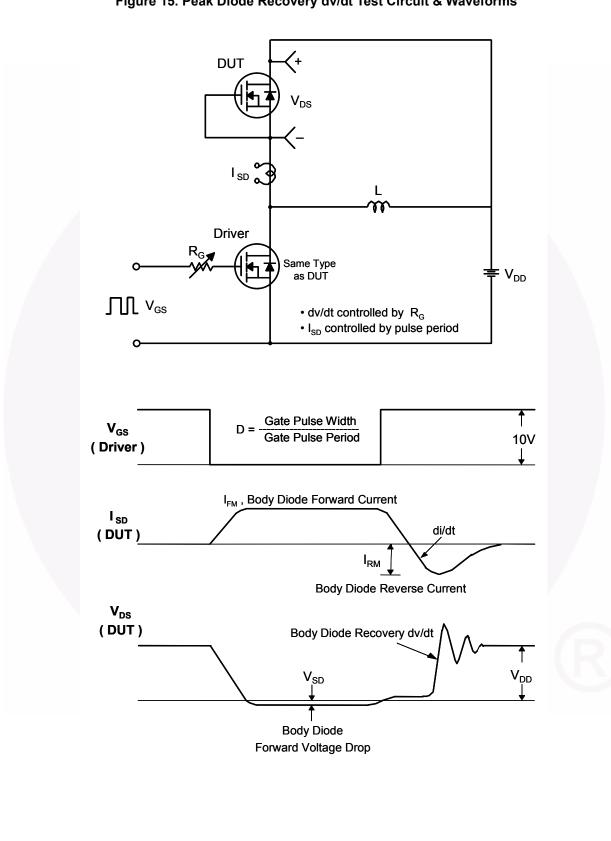
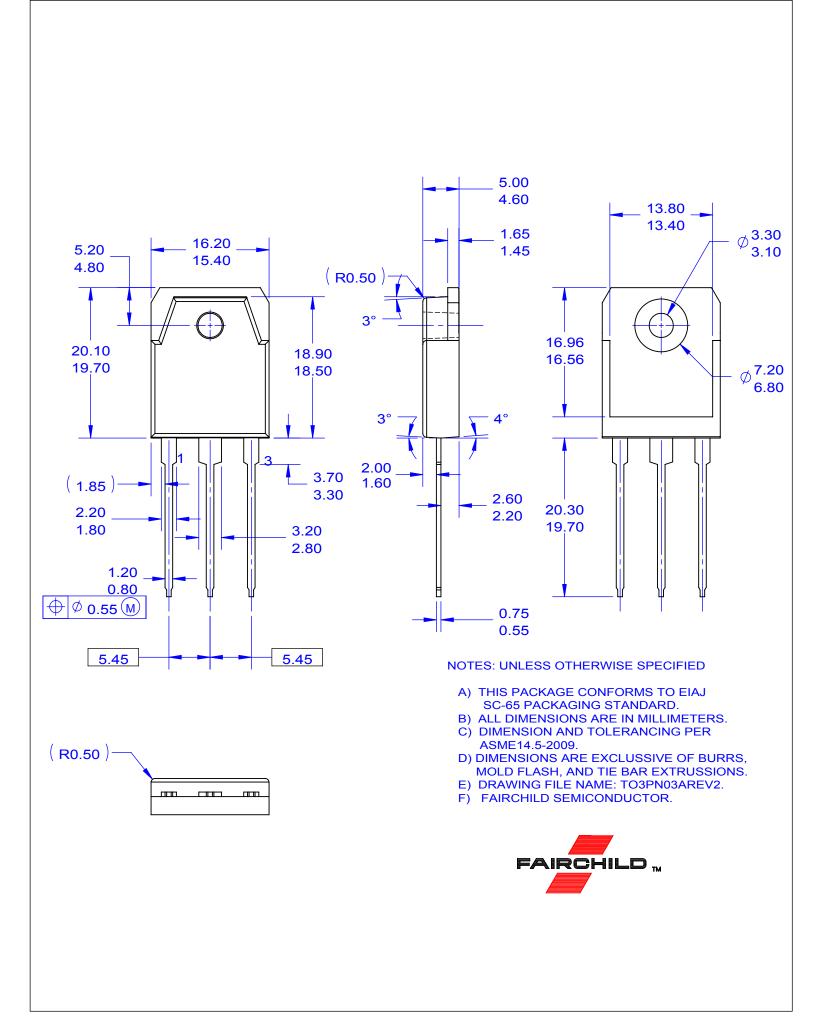
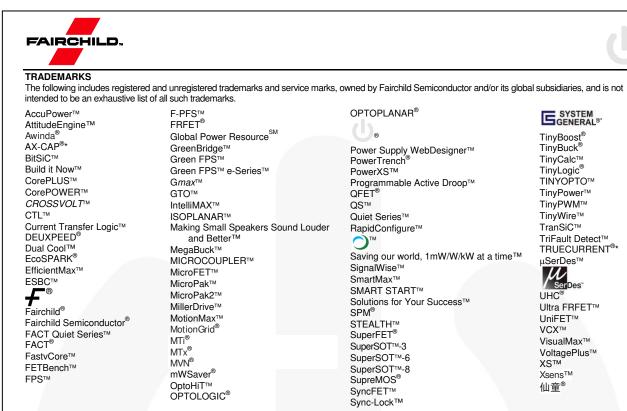


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms





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